# Quad Low-Power, 500Mbps ATE Driver/Comparator 

## General Description

The MAX9965/MAX9966 four-channel, low-power, highspeed pin electronics driver and comparator ICs include for each channel a three-level pin driver, comparator, and variable clamps. The MAX9965/MAX9966 are similar to the MAX9963/MAX9964, but with even lower window comparator dispersion for enhanced accuracy. The driver features a wide voltage range and high-speed operation, includes high- $Z$ and active termination (3rd-level drive) modes, and is highly linear even at low-voltage swings. The dual bipolar-input comparator provides very low dispersion (timing variation) over a wide variety of input conditions. The clamps provide damping of high-speed DUT waveforms when the device is configured as a high-impedance receiver. High-speed, differential control inputs compatible with ECL, LVPECL, LVDS, and GTL levels are provided for each channel. ECL/LVPECL or flexible open-collector outputs are available for the comparators.
The A-grade version provides tight matching of gain and offset for the driver and comparator, allowing reference levels to be shared across multiple channels in cost-sensitive systems. For system designs that incorporate independent reference levels for each channel, the B-grade version is available at reduced cost.
Optional internal resistors at the high-speed inputs provide differential termination of LVDS inputs, while optional internal resistors provide the pullup voltage and source termination for open-collector comparator outputs. These features significantly reduce the discrete component count on the circuit board.
The MAX9965/MAX9966 operating range is -1.5 V to +6.5 V , with powerdissipation of only 975 mW per channel.
These devices are available in a 100 -pin, $14 \mathrm{~mm} \times$ 14 mm body, 0.5 mm pitch TQFP with an exposed 8 mm $\times 8 \mathrm{~mm}$ die pad on the top (MAX9965) or bottom (MAX9966) of the package for efficient heat removal. The MAX9965/MAX9966 are specified to operate with an internal die temperature of $+60^{\circ} \mathrm{C}$ to $+100^{\circ} \mathrm{C}$, and feature a die temperature monitor output.

## Applications

Memory Testers
Low-Cost Mixed-Signal/System-on-Chip Testers
Structural Testers
Pattern/Data Generators

Features

- Small Footprint: Four Channels in 0.4in ${ }^{2}$
- Low Power Dissipation: 975mW/Channel (typ)
- High Speed: 500Mbps at 3VP-P
- Very Low Timing Dispersion
- Wide Operating Range: -1.5 V to +6.5 V
- Active Termination (3rd-Level Drive)
- Low-Leakage Mode: 15nA Maximum
- Integrated Clamps
- Interface Easily with Most Logic Families
- Digitally Programmable Slew Rate
- Internal Logic Termination Resistors
- Low Gain and Offset Error

Ordering Information

| PART | TEMP RANGE | PIN-PACKAGE |
| :---: | :---: | :---: |
| MAX9965ADCCQ* | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 100 TQFP-EPR*** |
| MAX9965AKCCQ* | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 100 TQFP-EPR*** |
| MAX9965AGCCQ* | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 100 TQFP-EPR*** |
| MAX9965AHCCQ* | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 100 TQFP-EPR*** |
| MAX9965AJCCQ* | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 100 TQFP-EPR*** |
| MAX9965BDCCQ* | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 100 TQFP-EPR*** |
| MAX9965BKCCQ* | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 100 TQFP-EPR*** |
| MAX9965BGCCQ | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 100 TQFP-EPR*** |
| MAX9965BHCCQ* | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 100 TQFP-EPR*** |
| MAX9965BJCCQ | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 100 TQFP-EPR*** |
| MAX9966ADCCQ* | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 100 TQFP-EP** |
| MAX9966AKCCQ* | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 100 TQFP-EP** |
| MAX9966AGCCQ* | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 100 TQFP-EP** |
| MAX9966AHCCQ* | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 100 TQFP-EP** |
| MAX9966AJCCQ* | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 100 TQFP-EP** |
| MAX9966BDCCQ* | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 100 TQFP-EP** |
| MAX9966BKCCQ* | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 100 TQFP-EP** |
| MAX9966BGCCQ | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 100 TQFP-EP** |
| MAX9966BHCCQ* | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 100 TQFP-EP** |
| MAX9966BJCCQ* | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 100 TQFP-EP** |

*Future product-contact factory for availability.
**EP = Exposed pad.
***EPR = Exposed pad reversed.
Pin Configurations and Selector Guide appear at end of data sheet.

## Quad Low-Power, 500Mbps ATE Driver/Comparator

## ABSOLUTE MAXIMUM RATINGS



DLV_ to DTV_ ................................................................... $\pm 10 \mathrm{~V}$
CHV_or CLV_ to DUT_...................................................... $\pm 10 \mathrm{~V}$
$\mathrm{CH}_{-}, \mathrm{NCH}_{-}, \mathrm{CL}_{-}, \mathrm{NCL}$ to $\mathrm{GND} . . . . . . . . . . . . . . . . . . . . . . . . . . . . . .-2.5 \mathrm{~V}$ to +5 V Current into DHV_, DLV_, DTV_,

CHV_, CLV_, CPHV_, CPLV_-....................................... $\pm 10 \mathrm{~mA}$ Current into TEMP ...........................................-0.5mA to +20mA DUT_ Short Circuit to -1.5 V to +6.5 V .........................Continuous Power Dissipation ( $\mathrm{T}_{\mathrm{A}}=+70^{\circ} \mathrm{C}$ ) MAX9965_CCQ (derate $167 \mathrm{~mW} /{ }^{\circ} \mathrm{C}$ above $+70^{\circ} \mathrm{C}$ ) 13.3W*

MAX9966_CCQ (derate $47.6 \mathrm{~mW} /{ }^{\circ} \mathrm{C}$
above $+70^{\circ} \mathrm{C}$ )
. $3.8 \mathrm{~W}^{*}$
Storage Temperature Range ............................ $65^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$
Junction Temperature ................................................... $125^{\circ} \mathrm{C}$
Lead Temperature (soldering, 10s) ............................... $300^{\circ} \mathrm{C}$
*Dissipation wattage values are based on still air with no heat sink for the MAX9965 and slug soldered to board copper for the MAX9966. Actual maximum power dissipation is a function of users' heat extraction technique and may be substantially higher.
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

## ELECTRICAL CHARACTERISTICS

$\left(\mathrm{V}_{\mathrm{CC}}=+9.75 \mathrm{~V}, \mathrm{~V}_{\mathrm{EE}}=-5.25 \mathrm{~V}, \mathrm{~V}_{\mathrm{CCO}}^{-}, 2.5 \mathrm{~V}, \mathrm{SC} 1=\mathrm{SCO}=0, \mathrm{~V}_{\mathrm{CPHV}}=7.2 \mathrm{~V}, \mathrm{~V}_{\mathrm{CPLV}}=-2.2 \mathrm{~V}, \mathrm{~T}_{\mathrm{J}}=+85^{\circ} \mathrm{C}\right.$, unless otherwise noted. All temperature coefficients are measured at $T_{J}=+60^{\circ} \mathrm{C}$ to $+100^{\circ} \mathrm{C}$, unless otherwise noted.) (Note 1)

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| POWER SUPPLIES |  |  |  |  |  |  |
| Positive Supply | VCC |  | 9.5 | 9.75 | 10.5 | V |
| Negative Supply | VEE |  | -6.5 | -5.25 | -4.5 | V |
| Positive Supply | ICC | (Note 2) |  | 200 | 225 | mA |
| Negative Supply | IEE | (Note 2) |  | -370 | -425 | mA |
| Power Dissipation | PD | (Notes 2, 3) |  | 3.9 | 4.5 | W |
| DUT_CHARACTERISTICS |  |  |  |  |  |  |
| Operating Voltage Range Max | VDUT | (Note 4) | -1.5 |  | +6.5 | V |
| Leakage Current in High-Z Mode | IDUT | LLEAK $=0,0 \leq \mathrm{V}_{\text {DUT_ }} \leq 3 \mathrm{~V}$ |  |  | $\pm 2$ | $\mu \mathrm{A}$ |
|  |  | LLEAK $=0, \mathrm{~V}_{\text {DUT_- }}=-1.5 \mathrm{~V}, 6.5 \mathrm{~V}$ |  |  | $\pm 5$ |  |
| Leakage Current in Low-Leakage Mode | IDUT | LLEAK $=1,0 \leq \mathrm{V}_{\text {DUT }} \leq 3 \mathrm{~V}, \mathrm{~T}_{\mathrm{J}}<+90^{\circ} \mathrm{C}$ |  |  | $\pm 15$ | nA |
|  |  | LLEAK $=1, \mathrm{~V}_{\text {DUT }}=-1.5 \mathrm{~V}, \mathrm{~T}_{\mathrm{J}}<+90^{\circ} \mathrm{C}$ |  |  | $\pm 30$ |  |
|  |  | LLEAK $=1, \mathrm{~V}_{\text {DUT_ }}=6.5 \mathrm{~V}, \mathrm{~T}_{\mathrm{J}}<+90^{\circ} \mathrm{C}$ |  |  | $\pm 30$ |  |
| Combined Capacitance | CDut | Driver in term mode (DUT_ = DTV_) |  | 3 |  | pF |
|  |  | Driver in high-Z mode |  | 5 |  |  |
| Low-Leakage Enable Time |  | (Notes 5, 7) |  | 20 |  | $\mu \mathrm{s}$ |
| Low-Leakage Disable Time |  | (Notes 6, 7) |  | 20 |  | $\mu \mathrm{s}$ |
| Low-Leakage Recovery |  | Time to return to the specified maximum leakage after a $3 \mathrm{~V}, 4 \mathrm{~V} / \mathrm{ns}$ step at DUT_ (Note 7) |  | 10 |  | $\mu \mathrm{s}$ |

## Quad Low-Power, 500Mbps ATE Driver/Comparator

## ELECTRICAL CHARACTERISTICS (continued)

$\left(\mathrm{V}_{C C}=+9.75 \mathrm{~V}, \mathrm{~V}_{\mathrm{EE}}=-5.25 \mathrm{~V}, \mathrm{~V}_{\mathrm{CCO}}-=2.5 \mathrm{~V}, \mathrm{SC1}=\mathrm{SCO}=0, \mathrm{~V}_{\mathrm{CPHV}}=7.2 \mathrm{~V}, \mathrm{~V}_{C P L V}=-2.2 \mathrm{~V}, \mathrm{~T}_{\mathrm{J}}=+85^{\circ} \mathrm{C}\right.$, unless otherwise noted. All temperature coefficients are measured at $\mathrm{T}_{J}=+60^{\circ} \mathrm{C}$ to $+100^{\circ} \mathrm{C}$, unless otherwise noted.) (Note 1)

| PARAMETER | SYMBOL | CONDITIONS |  | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| LEVEL PROGRAMMING INPUTS (DHV_, DLV_, DTV_, CHV_, CLV_, CPHV_, CPLV_) |  |  |  |  |  |  |  |
| Input Bias Current | IBIAS |  |  |  |  | $\pm 25$ | $\mu \mathrm{A}$ |
| Settling Time |  | To 5mV |  |  | 1 |  | $\mu \mathrm{s}$ |
| DIFFERENTIAL CONTROL INPUTS (DATA_, NDATA_, RCV_, NRCV_) |  |  |  |  |  |  |  |
| Input High Voltage | $\mathrm{V}_{\mathrm{IH}}$ |  |  | -1.6 |  | +3.5 | V |
| Input Low Voltage | $\mathrm{V}_{\text {IL }}$ |  |  | -2.0 |  | +3.1 | V |
| Differential Input Voltage | VIIFF |  |  | $\pm 0.15$ |  | $\pm 1.0$ | V |
| Input Resistor |  | MAX996__GCCQ, MAX996_ between signal and complem |  | 96 |  | 104 | $\Omega$ |
| SINGLE-ENDED CONTROL INPUTS ( $\overline{\mathrm{CS}}, \overline{\mathrm{RST}}, \mathrm{SCLK}, \mathrm{DIN}$ ) |  |  |  |  |  |  |  |
| Input High Voltage | $\mathrm{V}_{\mathrm{IH}}$ |  |  | 1.6 |  | 3.5 | V |
| Input Low Voltage | $\mathrm{V}_{\text {IL }}$ |  |  | -0.1 |  | +0.9 | V |
| SERIAL INTERFACE TIMING (Figure 5) |  |  |  |  |  |  |  |
| SCLK Frequency | fSCLK |  |  |  |  | 50 | MHz |
| SCLK Pulse Width High | tch |  |  | 8 |  |  | ns |
| SCLK Pulse Width Low | tCL |  |  | 8 |  |  | ns |
| $\overline{\text { CS }}$ Low to SCLK High Setup | tcsso |  |  | 3.5 |  |  | ns |
| $\overline{\overline{C S}}$ High to SCLK High Setup | tCSS1 |  |  | 3.5 |  |  | ns |
| SCLK High to $\overline{\mathrm{CS}}$ High Hold | tCSH1 |  |  | 3.5 |  |  | ns |
| DIN to SCLK High Setup | tDS |  |  | 3.5 |  |  | ns |
| DIN to SCLK High Hold | tD |  |  | 3.5 |  |  | ns |
| $\overline{\overline{C S}}$ Pulse Width High | tcswh |  |  | 20 |  |  | ns |
| TEMPERATURE MONITOR (TEMP) |  |  |  |  |  |  |  |
| Nominal Voltage |  | $\mathrm{T}_{J}=+70^{\circ} \mathrm{C}, \mathrm{R}_{\mathrm{L}} \geq 10 \mathrm{M} \Omega$ |  |  | 3.43 |  | V |
| Temperature Coefficient |  |  |  |  | +10 |  | $\mathrm{mV} /{ }^{\circ} \mathrm{C}$ |
| Output Resistance |  |  |  |  | 15 |  | $\mathrm{k} \Omega$ |
| DRIVERS (Note 8) |  |  |  |  |  |  |  |
| DC OUTPUT CHARACTERISTICS ( $\mathrm{R}_{\mathrm{L}} \geq 10 \mathrm{M} \Omega$ ) |  |  |  |  |  |  |  |
| DHV_, DLV_, DTV_, Output Offset Voltage | Vos | $\begin{aligned} & \text { At DUT_ with } V_{D H V}=3 \mathrm{~V}, \\ & \mathrm{~V}_{\text {DTV }}=1.5 \mathrm{~V}, \mathrm{~V}_{\text {DLV }}=0 \end{aligned}$ | MAX996_B |  |  | $\pm 100$ | mV |
| DHV_, DLV_, DTV_, Gain | Av | Measured with VDHV_, VDLV_, VDTV_ at 0 and 4.5 V | MAX996_B | 0.96 |  | 1.001 | V/V |
| DHV_, DLV_, DTV_, Output Voltage Temperature Coefficient |  | Includes both gain and offset temperature effects |  |  | $\pm 75$ |  | $\mu \mathrm{V} /{ }^{\circ} \mathrm{C}$ |
| Linearity Error |  | OV $\leq \mathrm{V}_{\text {DUT_ }} \leq 3 \mathrm{~V}$ (Note 9) |  |  |  | $\pm 5$ | mV |
|  |  | Full range (Notes 9, 10) |  |  |  | $\pm 15$ |  |

## SERIAL INTERFACE TIMING (Figure 5)

DRIVERS (Note 8)

## Quad Low-Power, 500Mbps <br> ATE Driver/Comparator

## ELECTRICAL CHARACTERISTICS (continued)

$\left(\mathrm{V}_{\mathrm{CC}}=+9.75 \mathrm{~V}, \mathrm{~V}_{\mathrm{EE}}=-5.25 \mathrm{~V}, \mathrm{~V}_{\mathrm{CCO}}^{-}=2.5 \mathrm{~V}, \mathrm{SC1}=\mathrm{SCO}=0, \mathrm{~V}_{\mathrm{CPHV}}=7.2 \mathrm{~V}, \mathrm{~V}_{\mathrm{CPLV}}=-2.2 \mathrm{~V}, \mathrm{TJ}^{2}=+85^{\circ} \mathrm{C}\right.$, unless otherwise noted. All temperature coefficients are measured at $\mathrm{T}_{J}=+60^{\circ} \mathrm{C}$ to $+100^{\circ} \mathrm{C}$, unless otherwise noted.) (Note 1)

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| DHV_ to DLV_ Crosstalk |  | $\mathrm{V}_{\text {DLV }}=0, \mathrm{~V}_{\text {DHV }}=200 \mathrm{mV}, 6.5 \mathrm{~V}$ |  |  | $\pm 2$ | mV |
| DLV_ to DHV_ Crosstalk |  | $\mathrm{V}_{\text {DHV }}=5 \mathrm{~V}, \mathrm{~V}_{\text {DLV }}=-1.5 \mathrm{~V}, 4.8 \mathrm{~V}$ |  |  | $\pm 2$ | mV |
| DTV_ to DLV_ and DHV_ Crosstalk |  | $\begin{aligned} & V_{D H V_{-}}=3 \mathrm{~V}, V_{D L V_{-}}=0, \\ & V_{D T V_{-}}=-1.5 \mathrm{~V},+6.5 \mathrm{~V} \end{aligned}$ |  |  | $\pm 2$ | mV |
| DHV_ to DTV_ Crosstalk |  | $\mathrm{V}_{\text {DTV_- }}=1.5 \mathrm{~V}, \mathrm{~V}_{\text {DLV }}=0, \mathrm{~V}_{\text {DHV }}=1.6 \mathrm{~V}, 3 \mathrm{~V}$ |  |  | $\pm 3$ | mV |
| DLV_ to DTV_ Crosstalk |  | $\mathrm{V}_{\text {DTV }}=1.5 \mathrm{~V}, \mathrm{~V}_{\text {DHV }}=3 \mathrm{~V}, \mathrm{~V}_{\text {DLV }}=0,1.4 \mathrm{~V}$ |  |  | $\pm 3$ | mV |
| DHV_, DLV_, DTV_ <br> DC Power-Supply Rejection Ratio | PSRR | $V_{C C}$ and $V_{E E}$ independently set to their $\mathrm{min} / \mathrm{max}$ values | 40 |  |  | dB |
| Maximum DC Drive Current | IDUT_ |  | $\pm 60$ |  | $\pm 120$ | mA |
| DC Output Resistance | RDUT_ | IDUT_ = $\pm 30 \mathrm{~mA}$ ( Note 11) | 49 | 50 | 51 | $\Omega$ |
| DC Output Resistance Variation | $\Delta$ RUUT_ | IDUT_ $= \pm 1.0 \mathrm{~mA}$ to $\pm 40 \mathrm{~mA}$ |  | 1 | 2.5 | $\Omega$ |
| DYNAMIC OUTPUT CHARACTERISTICS ( $\mathrm{Z}_{\mathrm{L}}=50 \Omega$ ) |  |  |  |  |  |  |
| Drive Mode Overshoot |  | $V_{D L V}=0, V_{\text {DHV }}=0.1 \mathrm{~V}$ |  | 30 |  | mV |
|  |  | $V_{D L V}=0, V_{\text {DHV }}=1 \mathrm{~V}$ |  | 40 |  |  |
|  |  | $V_{\text {DLV }}=0, V_{\text {DHV }}=3 \mathrm{~V}$ |  | 50 |  |  |
| Term Mode Overshoot |  | (Note 12) |  | 0 |  | mV |
| Settling Time to Within 25 mV |  | 3V step (Note 13) |  | 10 |  | ns |
| Settling Time to Within 5 mV |  | 3V step (Note 13) |  | 20 |  | ns |
| TIMING CHARACTERISTICS ( $\mathrm{Z}_{\mathrm{L}}=50 \Omega$ ) (Note 14) |  |  |  |  |  |  |
| Prop Delay, Data to Output | tPDD |  |  | 2 | 2.75 | ns |
| Prop Delay Match, TLH vs. THL |  | 3VP-P |  | $\pm 50$ |  | ps |
| Prop Delay Match, Drivers Within Package |  | (Note 15) |  | 40 |  | ps |
| Prop Delay Temperature Coefficient |  |  |  | +3 |  | ps/ ${ }^{\circ} \mathrm{C}$ |
| Prop Delay Change vs. Pulse Width |  | $3 V_{\text {P-P, }} 40 \mathrm{MHz}$, 2.5 ns to 22.5 ns pulse width, relative to 12.5 ns pulse width |  | $\pm 60$ |  | ps |
| Prop Delay Change vs. Common-Mode Voltage |  | $\mathrm{V}_{\text {DHV }}-\mathrm{V}_{\text {DLV }}=1 \mathrm{~V}, \mathrm{~V}_{\text {DHV }}=0$ to 6 V |  | 85 |  | ps |
| Prop Delay, Drive to High-Z | tpdDz | $\mathrm{V}_{\text {DHV_ }}=1.0 \mathrm{~V}, \mathrm{~V}_{\text {DLV }}=-1.0 \mathrm{~V}, \mathrm{~V}_{\text {DTV }}=0$ |  | 2.9 |  | ns |
| Prop Delay, High-Z to Drive | tpDzD | $\mathrm{V}_{\text {DHV }}=1.0 \mathrm{~V}, \mathrm{~V}_{\text {DLV }}=-1.0 \mathrm{~V}, \mathrm{~V}_{\text {DTV }}=0$ |  | 2.9 |  | ns |
| Prop Delay, Drive to Term | tPDDT | $\mathrm{V}_{\text {DHV_ }}=3 \mathrm{~V}, \mathrm{~V}_{\text {DLV }}=0, \mathrm{~V}_{\text {DTV_ }}=1.5 \mathrm{~V}$ |  | 2.3 |  | ns |
| Prop Delay, Term to Drive | tPDTD | $\mathrm{V}_{\text {DHV_ }}=3 \mathrm{~V}, \mathrm{~V}_{\text {DLV }}=0, \mathrm{~V}_{\text {DTV_ }}=1.5 \mathrm{~V}$ |  | 2.0 |  | ns |
| DYNAMIC PERFORMANCE ( $\mathrm{Z}_{\mathrm{L}}=50 \Omega$ ) |  |  |  |  |  |  |
| Rise and Fall Time | $t_{\text {R }}, \mathrm{tF}^{\text {F }}$ | 0.2 VP-P, 20\% to 80\% |  | 330 |  | ps |
|  |  | 1 VP-P, 10\% to 90\% | 450 | 670 | 750 |  |
|  |  | 3 VP-P, 10\% to 90\% | 1.1 | 1.2 | 1.4 | ns |
|  |  | 5 VP-P, 10\% to 90\% |  | 2.0 |  |  |

## Quad Low-Power, 500Mbps ATE Driver/Comparator

## ELECTRICAL CHARACTERISTICS (continued)

$\left(\mathrm{V}_{\mathrm{CC}}=+9.75 \mathrm{~V}, \mathrm{~V}_{\mathrm{EE}}=-5.25 \mathrm{~V}, \mathrm{~V}_{\mathrm{CCO}}^{-}=2.5 \mathrm{~V}, \mathrm{SC1}=\mathrm{SCO}=0, \mathrm{~V}_{\mathrm{CPHV}}=7.2 \mathrm{~V}, \mathrm{~V}_{\mathrm{CPLV}}=-2.2 \mathrm{~V}, \mathrm{TJ}^{2}=+85^{\circ} \mathrm{C}\right.$, unless otherwise noted. All temperature coefficients are measured at $\mathrm{T}_{J}=+60^{\circ} \mathrm{C}$ to $+100^{\circ} \mathrm{C}$, unless otherwise noted.) (Note 1)

| PARAMETER | SYMBOL | CONDITIONS | MIN TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: |
| SC1 = 0, SC0 = 1 Slew Rate |  | Percent of full speed (SC0 = SC1 = 0), 3VP-P, 20\% to 80\% | 75 |  | \% |
| SC1 $=1, \mathrm{SC0}=0$ Slew Rate |  | Percent of full speed (SC0 = SC1 = 0), 3VP-P, 20\% to 80\% | 50 |  | \% |
| SC1 = 1, SC0 = 1 Slew Rate |  | Percent of full speed (SC0 = SC1 = 0), 3VP-P, 20\% to 80\% | 25 |  | \% |
| Minimum Pulse Width (Note 16) |  | $0.2 \mathrm{VP}_{\text {P-P }}, \mathrm{V}_{\text {DHV_ }}=0.2 \mathrm{~V}, \mathrm{~V}_{\text {DLV }}=0$ | 0.65 |  | ns |
|  |  | $1 \mathrm{~V}_{\text {P-P, }} \mathrm{V}_{\text {DHV }}=1 \mathrm{~V}, \mathrm{~V}_{\text {DLV }}=0$ | 1.0 |  |  |
|  |  | $3 \mathrm{~V}_{\text {P-P, }} \mathrm{V}_{\text {DHV }}=3 \mathrm{~V}, \mathrm{~V}_{\text {DLV }}=0$ | 2.0 |  |  |
|  |  | $5 \mathrm{VP}_{\text {P-P, }} \mathrm{V}_{\text {DHV }}=5 \mathrm{~V}, \mathrm{~V}_{\text {DLV }}=0$ | 2.9 |  |  |
| Data Rate (Note 17) |  | $0.2 \mathrm{~V}_{\text {P-P, }} \mathrm{V}_{\text {DHV_- }}=0.2 \mathrm{~V}, \mathrm{~V}_{\text {DLV- }}=0$ | 1700 |  | Mbps |
|  |  | $1 \mathrm{~V}_{\text {P-P, }} \mathrm{V}_{\text {DHV_- }}=1 \mathrm{~V}, \mathrm{~V}_{\text {DLV }}=0$ | 1000 |  |  |
|  |  | $3 \mathrm{~V}_{\text {P-P, }} \mathrm{V}_{\text {DHV }}=3 \mathrm{~V}, \mathrm{~V}_{\text {DLV }}=0$ | 500 |  |  |
|  |  | $5 \mathrm{~V}_{\text {P-P, }} \mathrm{V}_{\text {DHV_- }}=5 \mathrm{~V}, \mathrm{~V}_{\text {DLV }}=0$ | 350 |  |  |
| Dynamic Crosstalk |  | (Note 18) | 20 |  | mVP-P |
| Rise and Fall Time, Drive to Term | tDTR, tDTF | $\begin{aligned} & V_{\text {DHV_ }}=3 V, V_{D L V}=0, V_{D T V}=1.5 \mathrm{~V}, \\ & 10 \% \text { to } 90 \%(\text { Note 19) } \end{aligned}$ | 1.6 |  | ns |
| Rise and Fall Time, Term to Drive | ttDR, ttdF | $\begin{aligned} & V_{\text {DHV }}=3 V, V_{\text {DLV }}=0, V_{D T V}=1.5 \mathrm{~V}, \\ & 10 \% \text { to } 90 \%(\text { Note 19) } \end{aligned}$ | 0.7 |  | ns |

## COMPARATORS

DC CHARACTERISTICS

| Input Voltage Range | VIN | (Note 4) |  | -1.5 |  | +6.5 | V |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Differential Input Voltage | VDIFF |  |  | $\pm 8$ |  |  | V |
| Hysteresis | VHYST |  |  | 0 |  |  | mV |
| Input Offset Voltage | VOS | $\mathrm{V}_{\text {DUT_ }}=1.5 \mathrm{~V}$ | MAX996_B | $\pm 100$ |  |  | mV |
| Input Offset Voltage Temperature Coefficient |  |  |  | $\pm 50$ |  |  | $\mu \mathrm{V} /{ }^{\circ} \mathrm{C}$ |
| Common-Mode Rejection Ratio | CMRR | V${ }_{\text {DUT__ }}=-1.5 \mathrm{~V}, 6.5 \mathrm{~V}$ (Note 20) |  | 50 | 55 |  | dB |
| Linearity Error |  | $\mathrm{V}_{\text {DUT }}=1.5 \mathrm{~V}$ (Note 9) |  |  | $\pm 1$ | $\pm 5$ |  |
|  |  | VDUT_ $=-1.5 \mathrm{~V}$ and 6.5V (Note 9) |  |  | $\pm 1$ | $\pm 10$ | m |
| Power-Supply Rejection Ratio | PSRR | V${ }_{\text {DUT_- }}=-1.5 \mathrm{~V}, 6.5 \mathrm{~V}$ (Note 21) |  | 50 | 66 |  | dB |

AC CHARACTERISTICS (Note 22)

| Minimum Pulse Width | tPW(MIN) | (Note 23) | MAX996__GCCQ | 0.6 |  |
| :--- | :---: | :---: | :--- | :--- | :---: |
|  |  | MAX996__HCCQ, <br> MAX996__JCCQ | 0.9 | ns |  |
| Prop Delay | tPDL |  |  | 1.2 | 2.0 |
| Prop Delay Temperature <br> Coefficient |  |  | 2.6 | ns |  |

## Quad Low-Power, 500Mbps ATE Driver/Comparator

## ELECTRICAL CHARACTERISTICS (continued)

$\left(\mathrm{V}_{\mathrm{CC}}=+9.75 \mathrm{~V}, \mathrm{~V}_{\mathrm{EE}}=-5.25 \mathrm{~V}, \mathrm{~V}_{\mathrm{CCO}}^{-}=2.5 \mathrm{~V}, \mathrm{SC1}=\mathrm{SCO}=0, \mathrm{~V}_{\mathrm{CPHV}}=7.2 \mathrm{~V}, \mathrm{~V}_{\mathrm{CPLV}}=-2.2 \mathrm{~V}, \mathrm{TJ}^{2}=+85^{\circ} \mathrm{C}\right.$, unless otherwise noted. All temperature coefficients are measured at $\mathrm{T}_{J}=+60^{\circ} \mathrm{C}$ to $+100^{\circ} \mathrm{C}$, unless otherwise noted.) (Note 1)


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# Quad Low-Power, 500Mbps ATE Driver/Comparator 

## ELECTRICAL CHARACTERISTICS (continued)

$\left(\mathrm{V}_{\mathrm{CC}}=+9.75 \mathrm{~V}, \mathrm{~V}_{\mathrm{EE}}=-5.25 \mathrm{~V}, \mathrm{~V}_{\mathrm{CCO}}^{-}=2.5 \mathrm{~V}, \mathrm{SC1}=\mathrm{SCO}=0, \mathrm{~V}_{\mathrm{CPHV}}=7.2 \mathrm{~V}, \mathrm{~V}_{\mathrm{CPLV}}=-2.2 \mathrm{~V}, \mathrm{TJ}^{2}=+85^{\circ} \mathrm{C}\right.$, unless otherwise noted. All temperature coefficients are measūred at $\mathrm{T} J=+60^{\circ} \mathrm{C}$ to $+100^{\circ} \mathrm{C}$, unless otherwise noted.) (Note 1)

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Differential Rise Time | tR | 20\% to 80\% |  | 500 |  | ps |
| Differential Fall Time | $\mathrm{tF}_{\text {F }}$ | 20\% to 80\% |  | 500 |  | ps |
| CLAMPS |  |  |  |  |  |  |
| High Clamp Input Voltage Range | $\mathrm{V}_{\mathrm{CPH}}$ |  | -0.3 |  | +7.5 | V |
| Low Clamp Input Voltage Range | $\mathrm{V}_{\text {CPL }}$ |  | -2.5 |  | +5.3 | V |
| Clamp Offset Voltage | Vos | At DUT_ with IDUT_ $=1 \mathrm{~mA}, \mathrm{~V}_{\text {CPHV }}=1.5 \mathrm{~V}$ |  |  | $\pm 100$ | mV |
|  |  | At DUT_ with IDUT_ $=-1 \mathrm{~mA}, \mathrm{~V}_{\text {CPLV }}=1.5 \mathrm{~V}$ |  |  | $\pm 100$ |  |
| Offset Voltage Temperature Coefficient |  |  |  | $\pm 0.5$ |  | $\mathrm{mV} /{ }^{\circ} \mathrm{C}$ |
| Clamp Power-Supply Rejection | PSRR | $V_{C C}$ and $V_{E E}$ independently set to their min and max values, IDUT_ $=1 \mathrm{~mA}, \mathrm{~V}_{\text {CPHV_ }}=0$ | 40 |  |  | dB |
|  |  | $V_{C C}$ and $V_{E E}$ independently set to their min and max values, IDUT_ $=-1 \mathrm{~mA}, \mathrm{~V}_{\text {CPLV_ }}=0$ | 40 |  |  |  |
| Voltage Gain | AV |  | 0.96 |  | 1.00 | V/V |
| Voltage Gain Temperature Coefficient |  |  |  | -100 |  | ppm $/{ }^{\circ} \mathrm{C}$ |
| Clamp Linearity |  | $\begin{aligned} & \text { ldUT_ }=1 \mathrm{~mA}, \mathrm{~V}_{\text {CPLV_ }}=-1.5 \mathrm{~V}, \\ & \mathrm{~V}_{\text {CPHV_ }}=-0.3 \mathrm{~V} \text { to } 6.5 \mathrm{~V} \end{aligned}$ |  | $\pm 10$ |  | mV |
|  |  | $\begin{aligned} & l_{\text {ldUT_ }}=-1 \mathrm{~mA}, \mathrm{~V}_{\text {CPHV }}=6.5 \mathrm{~V}, \\ & \mathrm{~V}_{\text {CPLV_ }}=-1.5 \mathrm{~V} \text { to } 5.3 \mathrm{~V} \end{aligned}$ |  | $\pm 10$ |  |  |
| Short-Circuit Output Current | IDUT | $\mathrm{V}_{\text {CPHV_ }}=0, \mathrm{~V}_{\text {CPLV }}=-1.5 \mathrm{~V}, \mathrm{~V}_{\text {DUT_ }}=6.5 \mathrm{~V}$ | 50 |  | 95 | mA |
|  |  | $\mathrm{V}_{\text {CPLV_ }}=5 \mathrm{~V}, \mathrm{~V}_{\text {CPHV_ }}=6.5 \mathrm{~V}, \mathrm{~V}_{\text {DUT_ }}=-1.5 \mathrm{~V}$ | -95 |  | -50 |  |
| Clamp DC Impedance | Rout | $\begin{aligned} & \mathrm{V}_{\mathrm{CPHV}}=3 \mathrm{~V}, \mathrm{~V}_{\mathrm{CPLV}}=0, \\ & \mathrm{I}_{\mathrm{CUT}}=-5 \mathrm{~mA} \text { and }-15 \mathrm{~mA} \end{aligned}$ | 50 |  | 55 | $\Omega$ |
|  |  | $\begin{aligned} & \mathrm{V}_{\text {CPHV_ }}=3 \mathrm{~V}, \mathrm{~V}_{\mathrm{CPLV}_{=}}=0, \\ & \mathrm{l}_{\mathrm{DUT}}=5 \mathrm{~mA} \text { and } 15 \mathrm{~mA} \end{aligned}$ | 50 |  | 55 |  |

Note 1: All min and max limits are 100\% tested in production. Tests are performed at worst-case supply voltages where applicable.
Note 2: Total for quad device at worst-case setting. $R_{L} \geq 10 \mathrm{M} \Omega$. The applicable supply currents are measured with typical supply voltages.
Note 3: Does not include internal dissipation of the comparator outputs. With output loads of $50 \Omega$ to ( $\mathrm{VVCCO}_{\mathrm{V}}$ _ -2 V ), this adds 240mW typical to the total chip power (MAX996_ _HCCQ, MAX996_ _JCCQ).
Note 4: Provided that the Absolute Maximum Ratings are not exceeded, externally forced voltages may exceed this range.
Note 5: Transition time from LLEAK being asserted to leakage current dropping below specified limits.
Note 6: Transition time from LLEAK being deasserted to output returning to normal operating mode.
Note 7: Based on simulation results only.
Note 8: With the exception of Offset and Gain/CMRR tests, reference input values are calibrated for offset and gain.
Note 9: Relative to straight line between 0 and 3 V .
Note 10: Full ranges are $-1.3 \mathrm{~V} \leq \mathrm{V}_{\text {DHV }} \leq 6.5 \mathrm{~V},-1.5 \mathrm{~V} \leq \mathrm{V}_{\text {DTV }} \leq 6.5 \mathrm{~V},-1.5 \mathrm{~V} \leq \mathrm{V}_{\text {DLV }} \leq 6.3 \mathrm{~V}$.
Note 11: Nominal target value is $50 \Omega$. Contact factory for alternate trim selections within the $40 \Omega$ to $50 \Omega$ range.
 Measurement is made using the comparator.
Note 13: Measured from the crossing point of DATA_inputs to the settling of the driver output.

## Quad Low-Power, 500Mbps ATE Driver/Comparator

Note 14: Prop delays are measured from the crossing point of the differential input signals to the $50 \%$ point of expected output swing. Rise time of the differential inputs DATA_ and RCV_ is 250 ps ( $10 \%$ to $90 \%$ ).
Note 15: Rising edge to rising edge or falling edge to falling edge.
Note 16: Specified amplitude is programmed. At this pulse width, the output reaches at least $95 \%$ of its nominal (DC) amplitude. The pulse width is measured at DATA_.
Note 17: Specified amplitude is programmed. Maximum data rate specified in transitions per second. A square wave that reaches at least $95 \%$ of its programmed amplitude may be generated at one-half of this frequency.
Note 18: Crosstalk from any driver to the other three channels. Aggressor channel is driving $3 \mathrm{~V}_{\mathrm{P}-\mathrm{P}}$ into a $50 \Omega$ load. Victim channels are in term mode with $V_{D T V}=1.5 \mathrm{~V}$.
Note 19: Indicative of switching speed from DHV_ or DLV_ to DTV_ and DTV_ to DHV_ or DLV_ when VDLV_ < VDTV_ < VDHV. If $V_{D T V}$ < VDLV_ or $V_{D T V}$ > $>V_{D H V}$, switching speed is degraded by approximately a factor of 3 .
Note 20: Change in Offset Voltage over input range.
Note 21: Change in Offset Voltage with power supplies independently set to their minimum and maximum values.
Note 22: Unless otherwise noted, all Prop Delays are measured at $40 \mathrm{MHz}, \mathrm{V}_{\text {DUT }}=0$ to $2 \mathrm{~V}, \mathrm{~V}_{C H V}=\mathrm{V}_{\text {CLV }}=1 \mathrm{~V}$, slew rate $=2 \mathrm{~V} / \mathrm{ns}$, $Z_{S}=50 \Omega$, driver in Term Mode with $V_{D T V}=0 \mathrm{~V}$. Comparator outputs are terminated with $50 \Omega$ to $G N D$ at scope input with $\mathrm{V}_{\mathrm{CCO}} \quad=2 \mathrm{~V}$. Open-collector outputs are also terminated (internally or externally) with RTERM $=50 \Omega$ to $\mathrm{V}_{\text {CCO }}$. . Measured from V $\bar{V}_{\text {DUT_ }}$ crossing calibrated CHV_/CLV_ threshold to crossing point of differential outputs.
Note 23: $\mathrm{V}_{\text {DUT_ }}=0$ to $1 \mathrm{~V}, \mathrm{~V}_{C H V_{-}}=\mathrm{V}_{\mathrm{CLV}_{-}}=0.5 \mathrm{~V}$. At this pulse width, the output reaches at least $90 \%$ of its DC Voltage swing. The pulse width is measured at the crossing points of the differential outputs.
Note 24: Relative to propagation delay at $V_{C H V_{-}}=V_{C L V_{-}}=1.5 \mathrm{~V}$. $V_{\text {DUT_ }}=200 \mathrm{mV}$ P-p. Overdrive $=100 \mathrm{mV}$.

## Quad Low-Power, 500Mbps ATE Driver/Comparator

Typical Operating Characteristics


## Quad Low-Power, 500Mbps ATE Driver/Comparator



CROSSTALK TO DUT_FROM DTV WITH DUT_= DLV


DRIVER GAIN vs. TEMPERATURE


CROSSTALK TO DUT_FROM DTV_ WITH DUT = DHV


CROSSTALK TO DUT_FROM DLV_ WITH DUT_= DTV


DRIVER OFFSET vs. TEMPERATURE


CROSSTALK TO DUT_FROM DHV_ WITH DUT_= DLV


CROSSTALK TO DUT_FROM DHV WITH DUT_= DTV


COMPARATOR OFFSET vs. COMMON-MODE VOLTAGE


# Quad Low-Power, 500Mbps ATE Driver/Comparator 

Typical Operating Characteristics (continued)


COMPARATOR TRAILING EDGE TIMING ERROR vs. PULSE WIDTH, MAX996__GCCQ



COMPARATOR FALLING EDGE TIMING VARIATION vs. COMMON-MODE VOLTAGE


COMPARATOR TRAILING EDGE TIMING ERROR vs. PULSE WIDTH, MAX996_ _JCCQ


COMPARATOR DIFFERENTIAL OUTPUT RESPONSE (MAX996_ GCCQ)

$\mathrm{t}=2.50 \mathrm{~ns} / \mathrm{div}$
$V_{\text {DUT }}=0$ TO 3V PULSE, CHV_= CLV_ $=1.5 \mathrm{~V}$,
EXTERNAL LOAD $=50 \Omega$

COMPARATOR TIMING VARIATION vs. OVERDRIVE


COMPARATOR TIMING VARIATION vs. INPUT SLEW RATE, DUT_RISING


COMPARATOR DIFFERENTIAL OUTPUT RESPONSE (MAX996_ JCCQ)

$\mathrm{t}=2.50 \mathrm{~ns} / \mathrm{div}$
$V_{\text {DUT }}=0$ TO 3V PULSE, CHV_ $=$ CLV_ $=1.5 \mathrm{~V}$, EXTERNAL LOAD $=50 \Omega$

## Quad Low-Power, 500Mbps ATE Driver/Comparator



## Quad Low-Power, 500Mbps ATE Driver/Comparator

Typical Operating Characteristics (continued)




Icc vs. TEMPERATURE

DUT_ $_{-}=$DTV $_{-}=1.5 \mathrm{~V}$, DHV $_{-}=3 \mathrm{~V}, \mathrm{DLV}_{-}=0$,
$\mathrm{CHV}_{-}=$CLV_ $^{=}=0, \mathrm{CPHV}_{-}=7.2 \mathrm{~V}, \mathrm{CPLV}=-2.2 \mathrm{~V}$,
$V_{C C}=9.75 \mathrm{~V}, \mathrm{~V}_{\mathrm{EE}}=-5.25 \mathrm{~V}$

DUT_= DTV_ $=1.5 \mathrm{~V}$, DHV_ $_{-}=3 \mathrm{~V}, \mathrm{DLV}=0$,
$C H V=C L V=0, C P H V-=7.2 \mathrm{~V}, \mathrm{CPLV}=-2.2 \mathrm{~V}$,
$\mathrm{V}_{\mathrm{CC}}=9.75 \mathrm{~V}, \overline{\mathrm{~V}}_{\mathrm{EE}}=-5.25 \mathrm{~V}$

## Quad Low-Power, 500Mbps ATE Driver/Comparator

| PIN |  | NAME |  |
| :---: | :---: | :---: | :--- |
| MAX9965 | MAX9966 |  |  |
| 1 | 25 | VCCO34 | Channel 3/4 Collector Voltage Input. For open-collector outputs, this is the pullup <br> voltage for the internal termination resistors. For open-emitter outputs, this is the <br> collector voltage of the output transistors. Not internally connected on open-collector <br> versions without internal termination resistors. Vcco34 services both channel 3 and <br> channel 4. |
| 2 | 24 | DATA4 | Channel 4 Multiplexer Control Inputs. Differential controls DATA4 and NDATA4 select <br> driver 4's input from DHV4 or DLV4. Drive DATA4 above NDATA4 to select DHV4. Drive <br> NDATA4 above DATA4 to select DLV4. |
| 3 | 23 | NDATA4 |  |
| 4 | 22 | RCV4 | Channel 4 Multiplexer Control Inputs. Differential controls RCV4 and NRCV4 place <br> channel 4 into receive mode. Drive RCV4 above NRCV4 to place channel 4 into |
| receive mode. Drive NRCV4 above RCV4 to place channel 4 into drive mode. |  |  |  |

# Quad Low-Power, 500Mbps ATE Driver/Comparator 

Pin Description (continued)

| PIN |  | NAME | FUNCTION |
| :---: | :---: | :---: | :---: |
| MAX9965 | MAX9966 |  |  |
| 25 | 1 | Vccol2 | Channel 1/2 Collector Voltage Input. For open-collector outputs, this is the pullup voltage for the internal termination resistors. For open-emitter outputs, this is the collector voltage of the output transistors. Not internally connected on open-collector versions without internal termination resistors. VCCO12 services both channel 1 and channel 2. |
| 29 | 97 | NCL2 | Channel 2 Low Comparator Output. Differential output of channel 2 low comparator. |
| 30 | 96 | CL2 |  |
| 31 | 95 | NCH2 | Channel 2 High Comparator Output. Differential output of channel 2 high comparator. |
| 32 | 94 | CH 2 |  |
| 33 | 93 | NCL1 | Channel 1 Low Comparator Output. Differential output of channel 1 low comparator. |
| 34 | 92 | CL1 |  |
| 35 | 91 | NCH1 | Channel 1 High Comparator Output. Differential output of channel 1 high comparator. |
| 36 | 90 | CH 1 |  |
| 37 | 89 | CPHV2 | Channel 2 High Clamp Reference Input |
| 38 | 88 | CPLV2 | Channel 2 Low Clamp Reference Input |
| 39 | 87 | DHV2 | Channel 2 Driver High Reference Input |
| 40 | 86 | DLV2 | Channel 2 Driver Low Reference Input |
| 41 | 85 | DTV2 | Channel 2 Driver Termination Reference Input |
| 42 | 84 | CHV2 | Channel 2 High Comparator Reference Input |
| 43 | 83 | CLV2 | Channel 2 Low Comparator Reference Input |
| 44 | 82 | CPHV1 | Channel 1 High Clamp Reference Input |
| 45 | 81 | CPLV1 | Channel 1 Low Clamp Reference Input |
| 46 | 80 | DHV1 | Channel 1 Driver High Reference Input |
| 47 | 79 | DLV1 | Channel 1 Driver Low Reference Input |
| 48 | 78 | DTV1 | Channel 1 Driver Termination Reference Input |
| 49 | 77 | CHV1 | Channel 1 High Comparator Reference Input |
| 50 | 76 | CLV1 | Channel 1 Low Comparator Reference Input |
| 53 | 73 | DUT1 | Channel 1 Device Under Test Input/Output. Combined I/O for driver, comparator, and clamp. |
| 57, 69 | 57, 69 | N.C. | No Connect. Leave open. |
| 59 | 67 | DUT2 | Channel 2 Device Under Test Input/Output. Combined I/O for driver, comparator, and clamp. |
| 63 | 63 | TEMP | Temperature Monitor Output |

## Quad Low-Power, 500Mbps ATE Driver/Comparator

Pin Description (continued)

| PIN |  | NAME | FUNCTION |
| :---: | :---: | :---: | :---: |
| MAX9965 | MAX9966 |  |  |
| 67 | 59 | DUT3 | Channel 3 Device Under Test Input/Output. Combined I/O for driver, comparator, and clamp. |
| 73 | 53 | DUT4 | Channel 4 Device Under Test Input/Output. Combined I/O for driver, comparator, and clamp. |
| 76 | 50 | CLV4 | Channel 4 Low Comparator Reference Input |
| 77 | 49 | CHV4 | Channel 4 High Comparator Reference Input |
| 78 | 48 | DTV4 | Channel 4 Driver Termination Reference Input |
| 79 | 47 | DLV4 | Channel 4 Driver Low Reference Input |
| 80 | 46 | DHV4 | Channel 4 Driver High Reference Input |
| 81 | 45 | CPLV4 | Channel 4 Low Clamp Reference Input |
| 82 | 44 | CPHV4 | Channel 4 High Clamp Reference Input |
| 83 | 43 | CLV3 | Channel 3 Low Comparator Reference Input |
| 84 | 42 | CHV3 | Channel 3 High Comparator Reference Input |
| 85 | 41 | DTV3 | Channel 3 Driver Termination Reference Input |
| 86 | 40 | DLV3 | Channel 3 Driver Low Reference Input |
| 87 | 39 | DHV3 | Channel 3 Driver High Reference Input |
| 88 | 38 | CPLV3 | Channel 3 Low Clamp Reference Input |
| 89 | 37 | CPHV3 | Channel 3 High Clamp Reference Input |
| 90 | 36 | CH 4 |  |
| 91 | 35 | NCH 4 | Channel 4 High Comparator Output. Differential outputs of channel 4 high comparator. |
| 92 | 34 | CL4 | Channel 4 Low Comparator Output Differential output |
| 93 | 33 | NCL4 | Channel 4 Low Comparator Output. Differential outputs of channel 4 low comparator. |
| 94 | 32 | CH3 | of channel 3 high |
| 95 | 31 | NCH3 | Channel 3 High Comparator Output. Diferential outputs of channel 3 high comparator. |
| 96 | 30 | CL3 | Channel 3 Low Comparator Output Differential outputs of chann |
| 97 | 29 | NCL3 | Channel 3 Low Comparator Output. Diferential output of channel 3 low comparator. |

## Quad Low-Power, 500Mbps ATE Driver/Comparator



Figure 1. MAX9965/MAX9966 Block Diagram

# Quad Low-Power, 500Mbps ATE Driver/Comparator 

__Detailed Description
The MAX9965/MAX9966 four-channel, high-speed pin electronics driver and comparator ICs for automatic test equipment include, for each channel, a three-level pin driver, a dual comparator, and variable clamps (Figure 1). The driver features a -1.5 V to +6.5 V operating range and high-speed operation, including high-Z and active termination (3rd-level drive) modes, which is highly linear even at low-voltage swings. The devices are similar to the MAX9963/MAX9964 but with a comparator that provides even lower timing dispersion, due to changes in input slew rate and pulse width. The clamps provide damping of high-speed DUT_ waveforms when the device is configured as a high-impedance receiver.
Each of the four channels has high-speed, differential inputs compatible with ECL, LVPECL, LVDS, and GTL signal levels, with optional $100 \Omega$ differential input terminations. Optional internal resistors at DATA_ and RCV_ provide differential termination of LVDS inputs. Optional internal resistors at $\mathrm{CH}_{-}$and $\mathrm{CL}_{\text {_ }}$ provide the pullup voltage and source termination for open-collector comparator outputs. These options significantly reduce the discrete component count on the circuit board.
The MAX9965/MAX9966 are available in two grade options. An A-grade version provides tighter matching of gain and offset of the drivers, and tighter offset matching of the comparators. This allows reference levels to be shared across multiple channels in cost-sensitive systems. A B-grade version provides lower cost for system designs that incorporate independent reference levels for each channel.

The MAX9965/MAX9966 modal operation is programmed through a 3-wire, low-voltage, CMOS-compatible serial interface.

## Output Driver

The driver input is a high-speed multiplexer that selects one of three voltage inputs: $D H V_{-}$, DLV_, or DTV_. This switching is controlled by high-speed inputs DATA_ and RCV_, and mode control bit TMSEL. A slew-rate circuit controls the slew rate of the buffer input. One of four possible slew rates can be selected (Table 1); the speed of the internal multiplexer sets the $100 \%$ driver slew rate (see the Driver Large-Signal Response in the Typical Operating Characteristics).
DUT_ can be toggled at high speed between the buffer output and high-impedance mode, or it can be placed in low-leakage mode (Figure 2, Table 2). In high-impedance mode, the clamps are connected. This switching is controlled by the high-speed input RCV_ and the mode control bits TMSEL and LLEAK. In high-impedance mode, the bias current at DUT_ is less than $2 \mu \mathrm{~A}$ over the 0 to 3 V range, while the node maintains its ability to track high-speed signals. In low-leakage mode, the bias current at DUT_ is further reduced to less than $15 n A$. See the Low-Leakage Mode section for more detailed information.
The nominal driver output resistance is $50 \Omega$. Contact the factory for different values within the $40 \Omega$ to $50 \Omega$ range.


Figure 2. Simplified Driver Channel

# Quad Low-Power, 500Mbps ATE Driver/Comparator 

Table 1. Slew Rate Logic

| SC1 | SC0 | DRIVER SLEW RATE (\%) |
| :---: | :---: | :---: |
| 0 | 0 | 100 |
| 0 | 1 | 75 |
| 1 | 0 | 50 |
| 1 | 1 | 25 |

## Table 2. Driver Logic

| EXTERNAL <br> CONNECTIONS |  | INTERNAL CONTROL <br> REGISTER |  | DRIVER OUTPUT |
| :---: | :---: | :---: | :---: | :--- |
| DATA_- | RCV_ | TMSEL | LLEAK |  |
| 1 | 0 | $X$ | 0 | Drive to DHV_- |
| 0 | 0 | $X$ | 0 | Drive to DLV_ |
| $X$ | 1 | 1 | 0 | Drive to DTV_ <br> (term mode) |
| $X$ | 1 | 0 | 0 | High-impedance <br> mode (high-z) |
| $X$ | $X$ | $X$ | 1 | Low-leakage mode |

Clamps
A pair of voltage clamps (high and low) can be configured to limit the voltage at DUT_, and to suppress reflections when the channel is configured as a highimpedance receiver. The clamps behave as diodes connected to the outputs of high-current buffers. Internal circuitry compensates for the diode drop at 1 mA clamp current. Set the clamp voltages using external connections CPHV_ and CPLV_. The clamps are enabled only when the driver is in the high-impedance mode (Figure 2). For transient suppression, set the clamp voltages to approximately the minimum and maximum expected DUT_ voltage range and must be empirically determined. The optimal clamp voltages are application specific. If clamping is not desired, set the clamp voltages at least 0.7 V outside the expected DUT_ voltage range; overvoltage protection remains active without loading DUT_.

Comparators
The MAX9965/MAX9966 have two independent highspeed comparators for each channel. Each comparator has one input connected internally to DUT_ and the other input connected to either $\mathrm{CHV}_{-}$or $\mathrm{CLV}_{-}$(Figure 1). Comparator outputs are a logical result of the input conditions, as indicated in Table 3.
The MAX9965/MAX9966s' comparators feature BJT inputs for improved comparator dispersion in contrast to the MAX9963/MAX9964s' JFET comparators.

Table 3. Comparator Logic

| DUT_ $_{-}$CHV $_{-}$ | DUT_ $_{-} \mathbf{C L V}_{-}$ | $\mathbf{C H}_{-}$ | $\mathbf{C L}_{-}$ |
| :---: | :---: | :---: | :---: |
| 0 | 0 | 0 | 0 |
| 0 | 1 | 0 | 1 |
| 1 | 0 | 1 | 0 |
| 1 | 1 | 1 | 1 |



Figure 3. Open-Collector Comparator Outputs


Figure 4. Open-Emitter Comparator Outputs

## Quad Low-Power, 500Mbps ATE Driver/Comparator

Three configurations are available for the comparator differential outputs to ease interfacing with a wide variety of logic families. An open-collector configuration switches an 8 mA current source between two outputs. This configuration is available with and without internal termination resistors connected to VCCO_ (Figure 3). For external termination, leave $\mathrm{VCCO}_{\mathrm{C}}$ unconnected and add the required external resistors. These resistors are typically $50 \Omega$ to the pullup voltage at the receiving end of the output trace. Alternate configurations may be used, provided that the Absolute Maximum Ratings are not exceeded. For internal termination, connect VCCO_ to the desired VOH voltage. Each output provides a nominal $400 \mathrm{mVP-P}$ swing and $50 \Omega$ source termination.
An open-emitter configuration is also available (Figure 4). Connect an external collector voltage to $\mathrm{VCCO}_{\mathrm{C}}$ and add external pulldown resistors. These are typically $50 \Omega$ to $\mathrm{VCCO}_{\mathrm{C}}-2 \mathrm{~V}$ at the receiving end of the output trace. Alternate configurations may be used, provided that the Absolute Maximum Ratings are not exceeded.

Low-Leakage Mode, LLEAK
Asserting LLEAK through the serial port or with RST places the MAX9965/MAX9966 into a very-low-leakage state in which the DUT_ input current is less than $15 n \mathrm{n}$ over the 0 to 3 V range. In this mode, the driver, comparators, and clamps are disabled. This mode is convenient for making IDDQ and PMU measurements without the need for an output disconnect relay. LLEAK is programmed independently for each channel. If DUT_ is driven with a high-speed signal while LLEAK is asserted, leakage current momentarily increases beyond the limits specified for normal operation. The Low-Leakage Recovery specification in the Electrical Characteristics table indicates device behavior under this condition.

Table 4. Shift Register Functions

| BIT | NAME | FUNCTION |
| :---: | :---: | :--- |
| D7 | 1E | Channel 1 Write Enable. Set to 1 to <br> update the control byte for channel 1. Set <br> to zero to make no change to channel 1. |
| D6 | $2 E$ | Channel 2 Write Enable. Set to 1 to <br> update the control byte for channel 2. Set <br> to zero to make no change to channel 2. |
| D5 | $3 E$ | Channel 3 Write Enable. Set to 1 to <br> update the control byte for channel 3. Set <br> to zero to make no change to channel 3. |
| D4 | 4 E | Channel 4 Write Enable. Set to 1 to <br> update the control byte for channel 4. Set <br> to zero to make no change to channel 4. |
| D3 | LLEAK | Low-Leakage Select. Set to 1 to put <br> driver and clamps into low-leakage <br> mode. Set to zero for normal operation. |
| D2 | SC1 | Driver Slew Rate Select. SC1 and SC0 <br> set the driver slew rate. See Table 1. |
| D1 | SC0 | Driver Termination Select. Set to 1 to <br> force the driver output to the DTV_ |
| voltage (term mode) when RCV_ = Set |  |  |
| to zero to place the driver into a high |  |  |
| impedance state (high-z mode) when |  |  |
| RCV_= 1. See Table 2. |  |  |



Figure 5. Serial Interface Timing

## Quad Low-Power, 500Mbps ATE Driver/Comparator



Figure 6. Serial Interface

Temperature Monitor
Each device supplies a single temperature output signal, TEMP, that asserts a nominal output voltage of 3.43 V at a die temperature of $+70^{\circ} \mathrm{C}(343 \mathrm{~K})$. The output voltage increases proportionately with temperature at a rate of $10 \mathrm{mV} /{ }^{\circ} \mathrm{C}$. The temperature sensor output impedance is $15 \mathrm{k} \Omega$ (typ).

## Serial Interface and Device Control

A CMOS-compatible serial interface controls the MAX9965/MAX9966 modes (Figure 6). Control data flow into a bit shift register (MSB first) and are latched when $\overline{\mathrm{CS}}$ is taken high, as shown in the serial timing diagram, Figure 5. Data from the shift register are then loaded into any or all of a group of four quad latches, determined by bits D4 through D7, as indicated in Figure 6 and Table 4. The quad latches contain the four mode bits for each channel of the quad pin driver. The mode bits, in conjunction with external inputs DATA_
and $\mathrm{RCV}_{-}$, manage the features of each channel, as shown in Tables 1 and 2. RST sets LLEAK $=1$ for all channels, forcing them into low-leakage mode. All other bits are unaffected. At power-up, hold $\overline{\text { RST }}$ low until $V_{C C}$ and $V_{E E}$ have stabilized.

Heat Removal
These devices require heat removal under normal circumstances through the exposed pad, either by soldering to circuit board copper (MAX9966) or by use of an external heat sink (MAX9965). The exposed pad is electrically at $V_{\text {EE }}$ potential for both package types, and must be either connected to $\mathrm{V}_{\mathrm{EE}}$ or isolated.

Chip Information
TRANSISTOR COUNT: 7293
PROCESS: Bipolar

## Quad Low-Power, 500Mbps <br> ATE Driver/Comparator

Selector Guide

| PART | ACCURACY GRADE | COMPARATOR OUTPUT TYPE | COMPARATOR OUTPUT TERMINATION | HIGH-SPEED DIGITAL INPUT TERMINATION | HEAT <br> EXTRACTION | PINPACKAGE |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| MAX9965ADCCQ* | A | Open collector | None | None | Top | 100 TQFP-EPR |
| MAX9965AKCCQ* | A | Open collector | None | $100 \Omega$ LVDS | Top | 100 TQFP-EPR |
| MAX9965AGCCQ* | A | Open collector | $50 \Omega$ to VCCO | $100 \Omega$ LVDS | Top | 100 TQFP-EPR |
| MAX9965AHCCQ* | A | Open emitter | None | None | Top | 100 TQFP-EPR |
| MAX9965AJCCQ* | A | Open emitter | None | $100 \Omega$ LVDS | Top | 100 TQFP-EPR |
| MAX9965BDCCQ* | B | Open collector | None | None | Top | 100 TQFP-EPR |
| MAX9965BKCCQ* | B | Open collector | None | $100 \Omega$ LVDS | Top | 100 TQFP-EPR |
| MAX9965BGCCQ | B | Open collector | $50 \Omega$ to VCCO_ | $100 \Omega$ LVDS | Top | 100 TQFP-EPR |
| MAX9965BHCCQ* | B | Open emitter | None | None | Top | 100 TQFP-EPR |
| MAX9965BJCCQ | B | Open emitter | None | $100 \Omega$ LVDS | Top | 100 TQFP-EPR |
| MAX9966ADCCQ* | A | Open collector | None | None | Bottom | 100 TQFP-EP |
| MAX9966AKCCQ* | A | Open collector | None | $100 \Omega$ LVDS | Bottom | 100 TQFP-EP |
| MAX9966AGCCQ* | A | Open collector | $50 \Omega$ to $\mathrm{V}_{\mathrm{CCO}}$ | $100 \Omega$ LVDS | Bottom | 100 TQFP-EP |
| MAX9966AHCCQ* | A | Open emitter | None | None | Bottom | 100 TQFP-EP |
| MAX9966AJCCQ* | A | Open emitter | None | $100 \Omega$ LVDS | Bottom | 100 TQFP-EP |
| MAX9966BDCCQ* | B | Open collector | None | None | Bottom | 100 TQFP-EP |
| MAX9966BKCCQ* | B | Open collector | None | $100 \Omega$ LVDS | Bottom | 100 TQFP-EP |
| MAX9966BGCCQ | B | Open collector | $50 \Omega$ to $\mathrm{VCCO}_{2}$ | $100 \Omega$ LVDS | Bottom | 100 TQFP-EP |
| MAX9966BHCCQ* | B | Open emitter | None | None | Bottom | 100 TQFP-EP |
| MAX9966BJCCQ* | B | Open emitter | None | $100 \Omega$ LVDS | Bottom | 100 TQFP-EP |

*Future product-contact factory for availability.

# Quad Low-Power, 500Mbps ATE Driver/Comparator 



## Quad Low-Power, 500Mbps ATE Driver/Comparator



Package Information
For the latest package outline information, go to www.maxim-ic.com/packages.

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